Application No. 10/755,848

NOV 0 3 2006

## **REMARKS**

Applicants respectfully request favorable reconsideration and a Notice of Allowance.

Applicants have amended independent claim 1 to incorporate language from previously presented claim 3, and to take into account the present specification disclosure at page 38, line 2 from the bottom, page 41, line 6, and page 16 in the paragraph bridging to page 70. The amended claim 1 therefore avoids new matter and does not present new issues for consideration in the application. The claim is presented in an effort to advance prosecution towards favorable resolution.

Applicants acknowledge the prior requirement for restriction and the prior traverse. It appears that claims 4-8 remain withdrawn from consideration and are not re-joined. Assuming that the remaining claims, 1-3, 9-10, are in form for allowance, then the withdrawn claims may be canceled in an Examiner's Amendment.

Since the method claims by definition relate back to the article claims, it is courteously requested that the Examiner re-consider re-joinding of the method claims.

Applicants respectfully traverse the rejection of claims 1-3 and 10 under 35 U.S.C. §102(b) over Maffitt et al. (U.S. Patent No. 4,114,983).

Applicants carefully considered the rejection of the cited Maffitt et al. reference. The amended claim 1 refers, among other things, to a range of 14.7 µm to 200 µm concerning the shortest distance between adjacent peaks of irregularities in unit cells. The recited range is considerably different than what is described in Maffitt et al. as a requirement that the separation of adjacent peaks is not greater than three times the maximum amplitude of the peak, *i.e.*, it is not greater than 480 nanometers. This is readily determined following perusal of Maffitt et al. at column 4, lines 37-48.

A nanometer is not a micron.

Therefore, the structural surface disclosed according to Maffitt et al. in column 4, lines 37-48 is different from and would not have suggested the surface roughness according to Applicants' specification, and certainly not as recited in Applicants' claims.

Therefore, it should necessarily, logically follow that the cited Maffitt et al. reference neither discloses, or would it have suggested both R(0) of 1% or less and R (30 or less)/R (0) of 0.001 or less.

R (0) is the regular reflectance along the regular reflection direction against incidence along the regular reflection direction against incidence aligned at any angle from 5 to 30 degrees from the normal line of the anti-glare film.

R (30 or more) is the reflectance against the incidence light, along a direction inclined by 30 degrees or more toward the anti-glare film side from the normal reflection direction.

The Maffitt reference does not appear to disclose the "R" characteristics in FIG. 4 or in FIG. 7. Attention is respectfully invited to column 3, lines 25, 30 and 40-45, and column 7, line 61, *infra*.

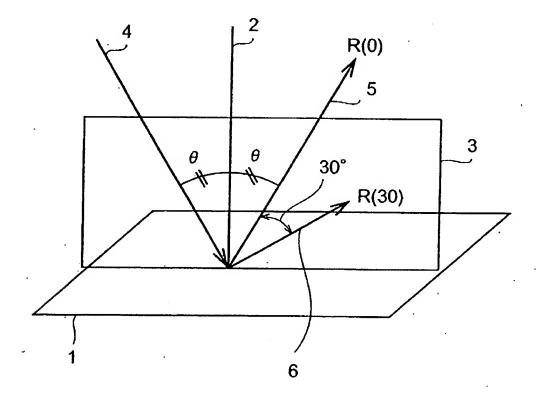
The Office Action refers to the Maffitt reference at column 9, lines 1-5. Applicants respectfully request clarification. It is not presently seen where this cited passage discloses or would have suggested both R (0) and R (30 or more).

Applicants further more respectfully submit the Maffitt reference does not describe the peak distribution according to claim 3. The article of the reference does not meet R (0) and R (30 or more). Besides, the assumption giving rise to the further assumption as to the peak distribution is mistaken.

Applicants present an explanation to further assist the Examiner in the review of the application. The Fig. 1 herein below represents a total reflection spectrum of a film according to an example in the present application. As used in the Figure, total has the same meaning as

shown in Maffitt et al. at a column 7, lines 66-68, which includes specular and diffuse reflection. A total reflection spectrum is measured by a spectral meter with intergrading sphere to collect specular and diffuse reflected light. It will be appreciated from the reflection spectrum of Applicants' anti-glare film obtained according to Example 1 herein, that it is <u>not</u> similar to Fig. 4B of Maffitt et al. On the other hand, the Maffitt et al. Fig. 4A is not used for an untreated CIB article, and is considered as not satisfying Applicants' claim limitations. Accordingly, both the explanation and Fig. 1 presented herein below support Applicants' position that their claims define novel invention over the Maffitt et al. reference. It of course also follows that the distinctions and benefits means that Applicants' claims are to unobvious inventions.

Fig. 1



Again, to bring the argument full circle, the size of a surface roughness considerably differs as between the Maffitt et al. reference and the present claimed invention. The difference is on the orders of magnitude. As the Examiner can appreciate, light behavior varies totally as between two distinct media, especially, whereas here, the surface roughness of one media is completely different from the surface roughness of the other.

Applicants traverse the rejection of claim 9 under 35 U.S.C. §103(a) over the Maffitt et al. reference.

Claim 9 is Applicants' invention, not Maffitt's.

Yet, the Office Action asserts in an apparent *ipse dixit* that "it would have been obvious ... to use the film of Maffitt et al. over any type of known display ...in view of the teachings ... by Maffitt et al." Whatever the Maffitt reference says that about Maffitt's invention seems wide of the mark. Applicants submit it does not teach their invention(s). The Maffitt disclosure is not a description or suggestion of their claimed anti-glare film.

The reference to the inherency principles in the Office Action should be reconsidered and withdrawn. It is respectfully suggested that the conjecture offered in the Office Action does not satisfy the strictly enforced factual predicate that the courts require before even considering whether to entertain an asserted inherency.

Therefore, Applicants earnestly submit the rejection should be withdrawn.

Applicants courteously solicit a Notice of Allowance.

Respectfully submitted,

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